

Form PTO-1449 (Rev. 8-83)	U.S. Department of Commerce Patent and Trademark Office	Attorney Docket No. 0756-2183	Serial No. Not Yet Assigned
INFORMATION DISCLOSURE STATEMENT <i>(Use several sheets if necessary)</i>		Applicant: Shunpei YAMAZAKI	
		Filing Date: July 20, 2000	Group: 2811

U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>AB</i>	4,849,081	7/18/89	Ross			
	3,607,679	9/1971	Melroy et al.			
	3,607,697	9/1971	Shim et al.			
	3,616,400	10/1971	Wasa et al.			
	3,763,026	10/1973	Cordes			
	4,515,668	5/1985	Brownell et al.			
	4,849,081	7/1989	Ross			
	4,732,659	3/1988	Schachter et al.			
	4,790,920	12/1988	Krzanich			
	4,804,640	2/1989	Kaganowicz et al.			
<i>AB</i>	4,883,543	11/1989	Gossen, Jr. et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation Yes No
<i>AB</i>	26-40078	7/8/90	France			X
<i>AB</i>	02-61128	11/1987	Japan			
<i>AB</i>	10-96925	12/1967	Great Britain			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>AB</i>	Young et al., "Correlation... Ta ₂ O ₅ films", J. Fac. Sci. Technol., Vol. 14, No. 1, Jan/Feb 1977.
<i>AB</i>	Schrieber et al., J. Electrochem Soc., Vol. 123, No. 1, pp. 30-33 (1976)
<i>AB</i>	Suyama et al., "Electrical Conduction Mechanism and Breakdown Property in Sputter-Deposited Silicon Dioxide Films on Polycrystalline Silicon", J. Appl. Phys., Vol 65, No. 1, 1 January 1989, pp. 210-214
<i>AB</i>	Jones et al., "Effect of Oxygen on the rf-Sputtering Rate of SiO ₂ ", J. Vacuum Sci. and Technology, Vol. 5, No. 3, pp. 84-87.
<i>AB</i>	Kozuma et al., "Some Properties of Silica Film Made by RF Glow Discharge Sputtering", J. Jap of Appl. Phys., vol. 9, No. 8, August 1970, pp. 983-91.
<i>AB</i>	Suyama et al., Chem. Abstracts 109573w, March 12, 1990, p. 750.

Examiner *Dolan C. et al.* Date Considered *10/24/05*

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
	4,951,175	8/1990	Kurosawa et al.				
	5,006,481	4/1991	Chan et al.				
	5,043,298	8/1991	Yamada et al.				
	4,350,537	9/1982	Young et al.				
	4,427,723	1/1984	Swain				
	4,539,431	9/1985	Moddel et al.				
	5,203,929	4/1993	Takayanagi et al.				
	4,849,081	7/18/89	Ross				
	5,665,210	9/9/97	Yamazaki				
	4,581,248	4/1986	Roche				
	4,624,736	11/1986	Gee et al.				
	4,906,328	3/1990	Freeman et al.				
	4,987,008	1/1991	Yamazaki et al.				
	5,213,997	5/1993	Ishihara et al.				
	4,888,630	12/19/89	Paterson				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
	Croteau et al. "Growth and Characterisation of PD(Zr, Ti) ^{0.3} Films Deposited by Reactive Sputtering of Metallic Targets" Proceedings of the Sixth IEEE International Symposium on Applications of Ferroelectrics, pp. 606-609, 1986.						
	definition from Merriam Webster Collegiate Dictionary, Tenth Edition						
	IEDM 11-14 Dec. 1988, pp. 222-225, San Francisco, Calif., U.S.; H. Takato et al; "High Performance CMOS Surrounding Gate Transistor (SGT) for Ultra High Density LSIs".						
	Mizuno et al., "High Speed and Highly Reliable Trench MOSFET with Dual Gate", Symp. VLSI Tech. Dig. (1988), pp. 23-24.						
	Young et al., "Effect of Pulse Duration on the Annealing of Ion Implanted Silicon With a XeCl Excimer Laser and Solar Cells", Mat. Res. Soc. Symp. Proc., Vol. 13, 1983, pp. 401-406.						
	Schreiber et al., "High Quality RF-Sputtered Silicon Dioxide Layers", J. Electrochem. Soc., Vol. 123, No. 1, 1976, pp. 30-31.						
Examiner	<i>Makoto Ueda</i>		Date Considered	<i>9/23/05</i>			
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OCT 20 2003

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Applicant: Shunpei YAMAZAKI

Filing Date: July 20, 2000

Group: 2811

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>MT</i>	5,109,357	4/28/92	Eaton Jr.			
	5,136,534	8/1992	McDavid et al.			
	5,302,843	4/12/94	Yamazaki			
	5,403,763	4/4/95	Yamazaki			
	5,587,340	12/24/96	Yamazaki			
	5,464,780	11/7/95	Yamazaki			
	5,561,311	10/1/96	Hamamoto et al.			
	4,937,641	6/26/90	Sunami et al.			
	5,181,088	01/19/93	Makita et al.			
	5,587,340	12/24/96	Yamazaki			
	4,931,897	6/5/90	Tsukamoto			
	4,250,519	2/10/81	Mogi et al.			
	4,554,570	11/19/85	Jastrzebski et al.			
	4,649,406	3/10/87	Takemae et al.			
	4,734,384	3/29/88	Tsuchiya			
	4,786,953	11/22/88	Morie et al.			
	4,818,715	4/4/89	Chao			
	4,819,043	4/4/89	Yazawa et al.			
	4,845,539	7/4/89	Inoue			
	4,891,327	1/2/90	Okumura			
	4,920,065	4/24/90	Chin et al.			
	4,937,641	6/26/90	Sunami et al.			
	4,963,504	10/16/90	Huang			
	4,975,383	12/4/90	Baglee			
	5,017,504	5/21/91	Nishimura et al.			
	5,027,173	6/25/91	Satoh			
<i>MT</i>	5,032,882	7/16/91	Okumura et al.			
Examiner <i>Mathan W. Hsu</i>	Date Considered	<i>9/23/05</i>				

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INFORMATION DISCLOSURE STATEMENT OCT 20 2003 C24 (Use several sheets if necessary)				Applicant: Shunpei YAMAZAKI			
				Filing Date: July 20, 2000		Group: 2811	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
<i>M</i>		5,047,359	09/10/91	Nagatomo			
		5,047,812	10/10/91	Pfiester			
		5,053,842	10/01/91	Kojima			
		5,056,010	10/08/91	Huang			
		5,086,010	02/04/92	Kimura			
		5,189,503	2/23/93	Suguro			
<i>N</i>		5,136,534	08/04/92	McDavid et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation Yes No
<i>CJS</i>		2 103 879A	08/19/81	United Kingdom			Full
<i>N</i>		WO 89/02655	03/23/89	PCT			Full
		JP 01-171275	7/6/89	Japan			Abstract
		JP 62-23117	1/31/87	Japan			Abstract
		JP 62-298119	12/25/87	Japan			Abstract
		JP 02-47256	2/16/90	Japan			Abstract
		JP 03-16129	24/1/91	Japan			Abstract
		JP 03-79028	4/4/91	Japan			Abstract
		EP 445535	11/9/91	European			Full
		EP 349187	03/01/90	European			Full
		1-203666	8/16/89	Japan			X
		62-269363	11/21/87	Japan			X
		63-199456	8/17/88	Japan			X
		1-248557	10/4/89	Japan			X
<i>M</i>		2-79475	3/20/90	Japan			X
Examiner	<i>Nathan C. C. C.</i>		Date Considered	<i>9/22/05</i>			

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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation Yes No	
✓	JP 59-99726	6/8/84	Japan			Abstract	
✓	JP 64-82557	03/28/89	Japan			Abstract	
✓	JP 01-225148	09/08/89	Japan			Abstract	
✓	JP 04-61337	02/27/92	Japan			Abstract	
✓	60-005555	01/12/85	Japan			Abstract	
✓	60-218472	11/01/85	Japan			Abstract	
✓	61-119045	06/06/86	Japan			Abstract	
✓	62-056570	03/12/87	Japan			Abstract	
✓	63-096262	04/27/88	Japan			Abstract	
✓	1-218054	08/31/89	Japan			Abstract	
Examiner	<i>Matthew W. Clark</i>		Date Considered	<i>9/24/05</i>			
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Case Docket 0756-2183

Serial No. 09 620,968

C INFORMATION DISCLOSURE STATEMENT

SEP 09 2000

Applicants: Shunpei YAMAZAKI

Filing Date: July 20, 2000

Group Art Unit: 2818

FOREIGN PATENT DOCUMENTS

Examiner Initials Initials	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
SEP 09 2000 JC	0 046 868	03/10/1982	EP			Full Eng	
	01-119055	05/11/1989	JP			Eng Abst	
	02-060157	02/28/1990	JP			Eng Abst	
	02-076257	03/15/1990	JP			Eng Abst	
	02-135777	05/24/1990	JP			Eng Abst	
N	57-045968	03/16/1982	jp			Eng Abst	

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Examiner *Matthew C. Cello*

Date Considered

a/24/05

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